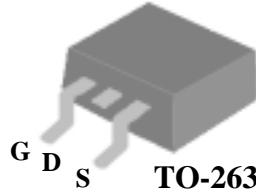


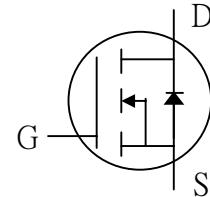
**N-CHANNEL ENHANCEMENT-MODE
POWER MOSFET**
Low Gate Charge
Simple Drive Requirement
Fast Switching


BV_{DSS}	30V
$R_{DS(ON)}$	17mΩ
I_D	40A

Description

Power MOSFETs from Silicon Standard Corp. provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-263 package is widely preferred for all commercial and industrial surface mount applications and suited for low voltage applications such as DC/DC converters. The through-hole version (SSM40N03P) is available for low-footprint applications.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	40	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	30	A
I_{DM}	Pulsed Drain Current ¹	169	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation	50	W
	Linear Derating Factor	0.4	W/°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-c}	Thermal Resistance Junction-case	Max. 2.5	°C/W
R_{thj-a}	Thermal Resistance Junction-ambient	Max. 62	°C/W

Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

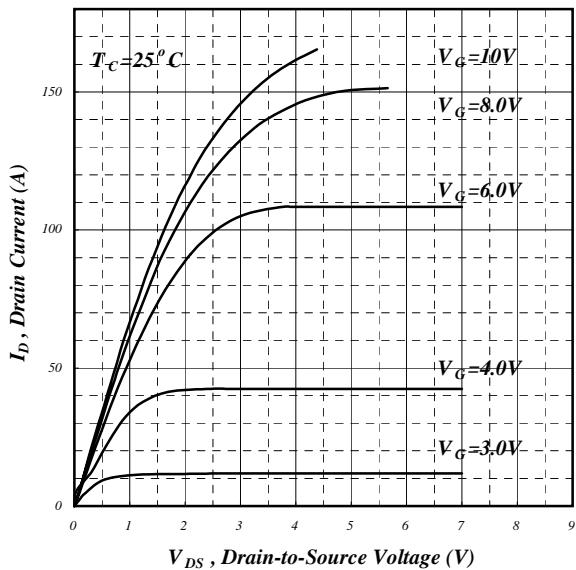
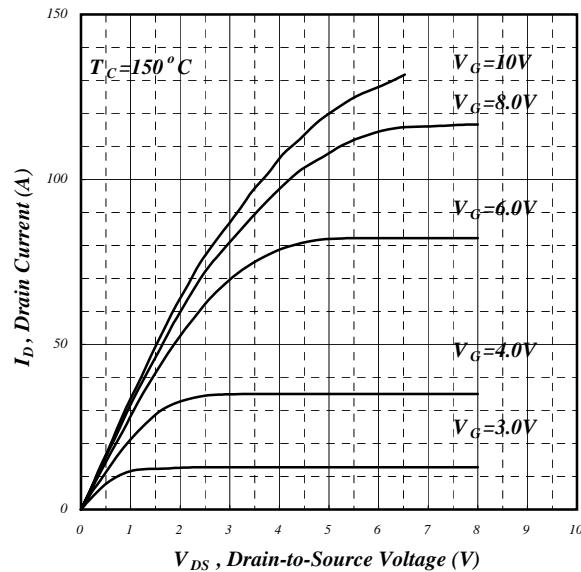
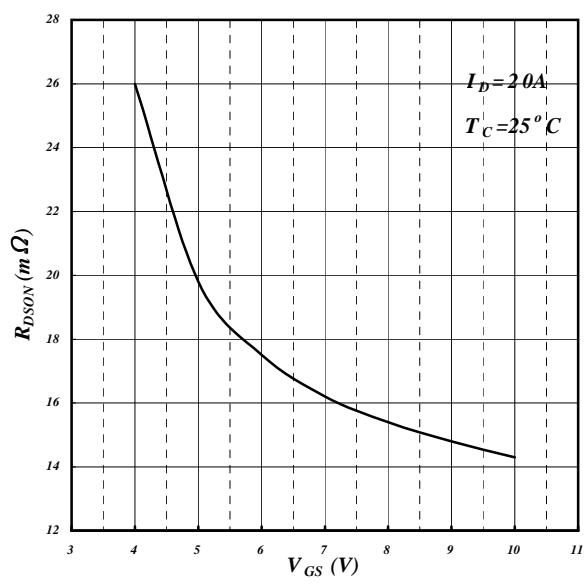
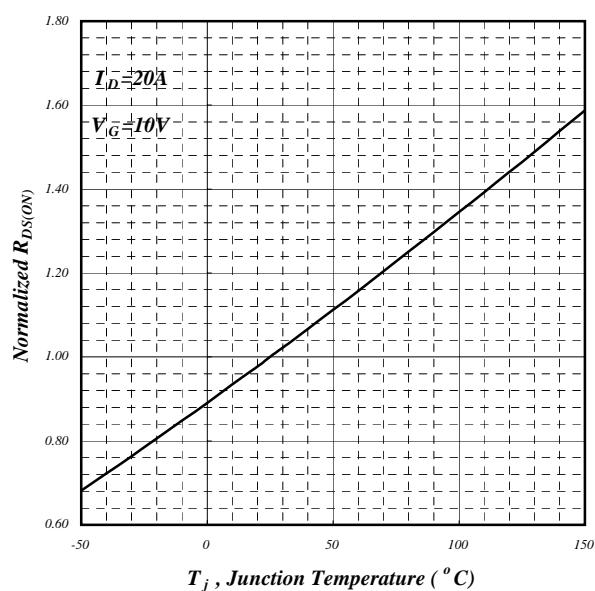
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	-	0.037	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}}=10\text{V}$, $I_D=20\text{A}$	-	14	17	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=16\text{A}$	-	20	23	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_D=20\text{A}$	-	26	-	S
I_{DSS}	Drain-Source Leakage Current ($T_j=25^\circ\text{C}$)	$V_{\text{DS}}=30\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	1	μA
	Drain-Source Leakage Current ($T_j=150^\circ\text{C}$)	$V_{\text{DS}}=24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	25	μA
I_{GSS}	Gate-Source Forward Leakage	$V_{\text{GS}}= \pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=20\text{A}$	-	17	-	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=24\text{V}$	-	3	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=5\text{V}$	-	10	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$V_{\text{DS}}=15\text{V}$	-	7.2	-	ns
t_r	Rise Time	$I_D=20\text{A}$	-	60	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G=3.3\Omega$, $V_{\text{GS}}=10\text{V}$	-	22.5	-	ns
t_f	Fall Time	$R_D=0.75\Omega$	-	10	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	800	-	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	380	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	133	-	pF

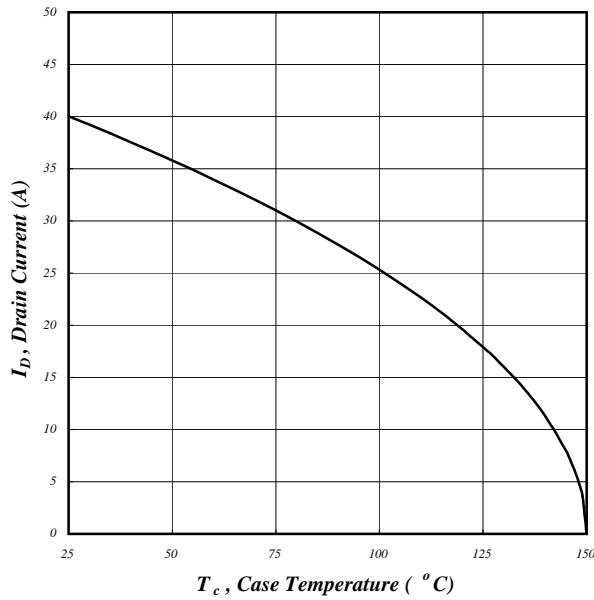
Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
I_s	Continuous Source Current (Body Diode)	$V_D=V_G=0\text{V}$, $V_S=1.3\text{V}$	-	-	40	A
I_{SM}	Pulsed Source Current (Body Diode) ¹		-	-	169	A
V_{SD}	Forward On Voltage ²	$T_j=25^\circ\text{C}$, $I_s=40\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V

Notes:

1. Pulse width limited by safe operating area.
2. Pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$.


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

Fig 3. On-Resistance v.s. Gate Voltage

Fig 4. Normalized On-Resistance v.s. Junction Temperature



**Fig 5. Maximum Drain Current v.s.
Case Temperature**

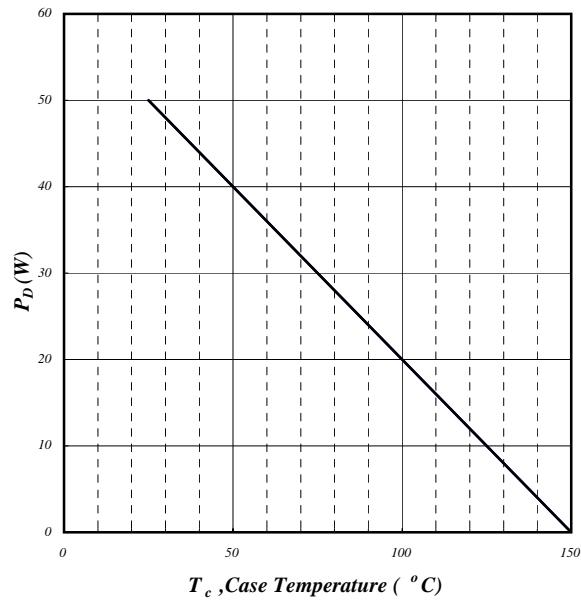


Fig 6. Typical Power Dissipation

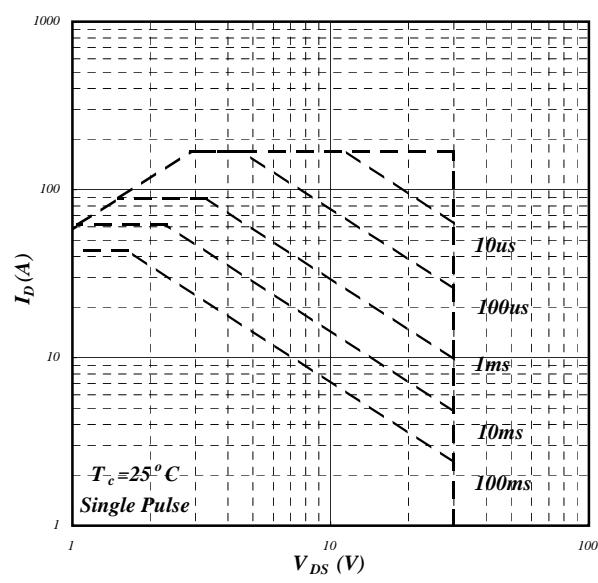


Fig 7. Maximum Safe Operating Area

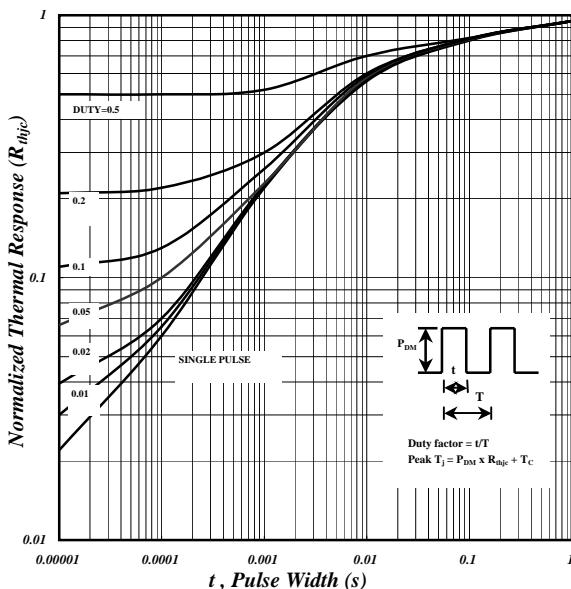
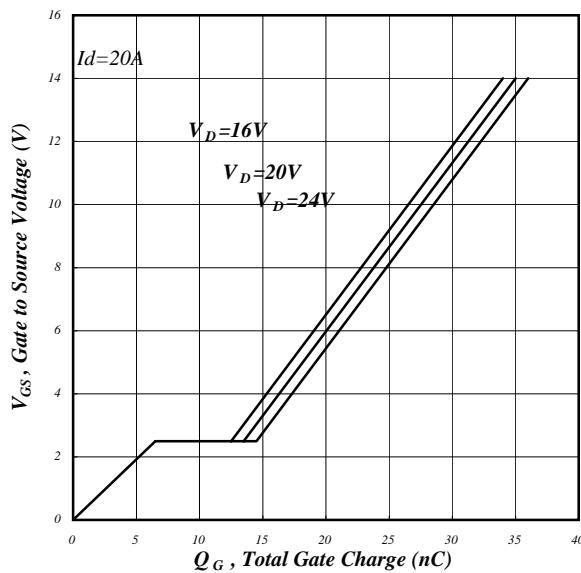
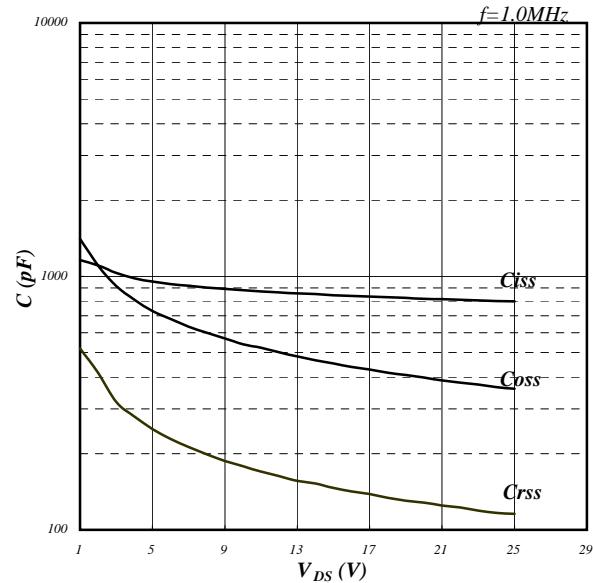
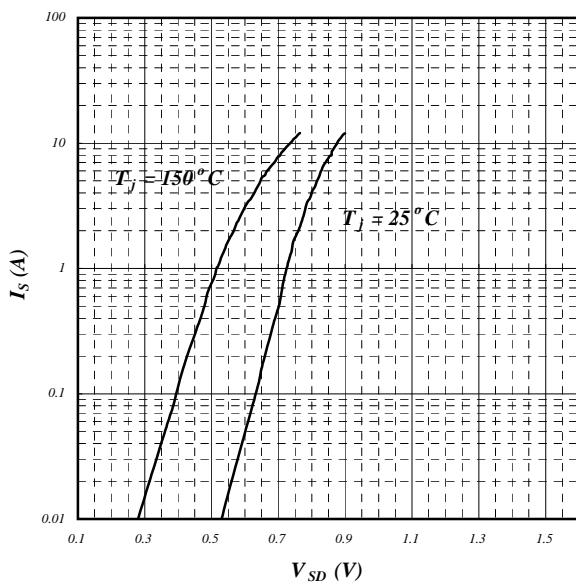
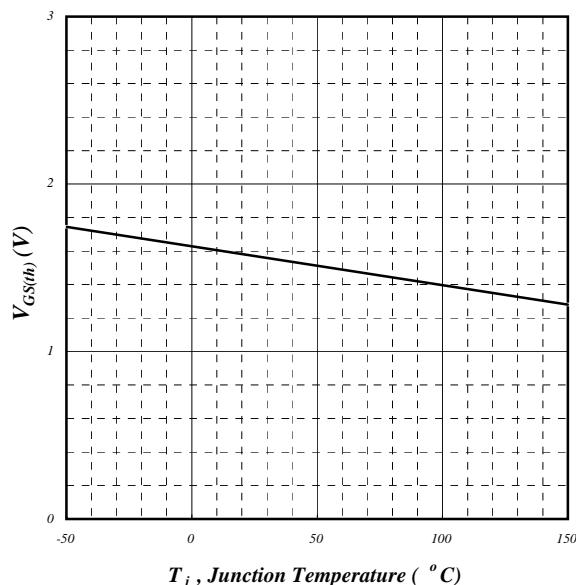
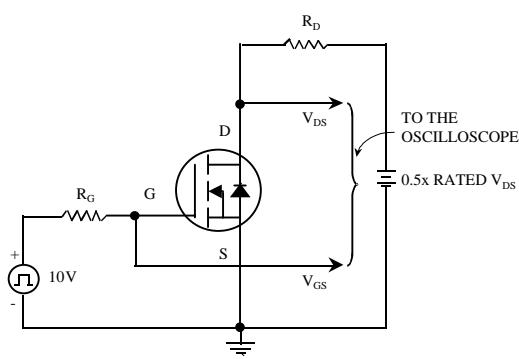
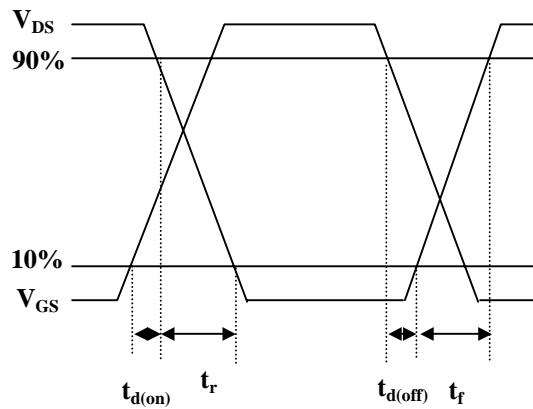
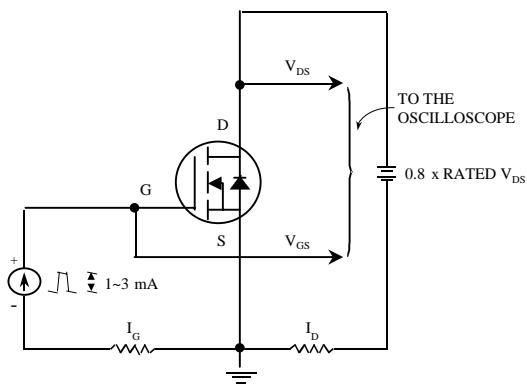
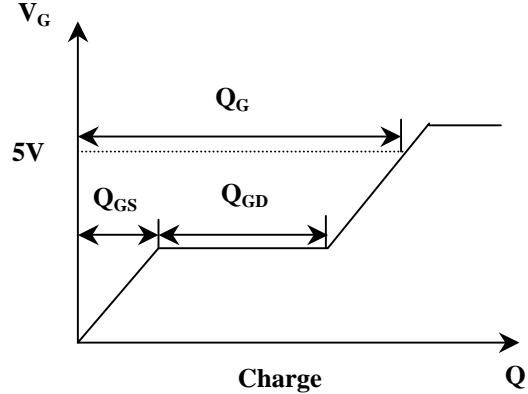


Fig 8. Effective Transient Thermal Impedance


Fig 9. Gate Charge Characteristics

Fig 10. Typical Capacitance Characteristics

Fig 11. Forward Characteristic of Reverse Diode

Fig 12. Gate Threshold Voltage v.s. Junction Temperature


Fig 13. Switching Time Circuit

Fig 14. Switching Time Waveform

Fig 15. Gate Charge Circuit

Fig 16. Gate Charge Waveform

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